# **NXT4557**

# SIM card interface level translator with enable pin

Rev. 2.2 — 31 July 2024

**Product data sheet** 

### 1. General description

The NXT4557 device is built for interfacing a SIM card with a single low-voltage host side interface. The NXT4557 has three level translators to convert the data, RST and CLK signals between a SIM card and a host microcontroller. A high speed level translation capable of supporting class-B, class-C SIM cards. An active HIGH EN pin enables normal operation of the translator. A HIGH to LOW transition on pin EN initiates a shutdown sequence on SIM card pins in accordance with ISO-7816-3.

The NXT4557 is compliant with all ETSI, IMT-2000 and ISO-7816 SIM/Smart card interface requirements.

### 2. Features and benefits

- Support SIM cards and eSIM with supply voltages 1.62 V to 3.3 V
- Host micro-controller operating voltage range: 1.08 V to 1.98 V
- Automatic level translation of I/O, RST and CLK between SIM card and host side interface with capacitance isolation
- Incorporates shutdown feature for the SIM card signals according to ISO-7816-3
- High V<sub>dis(UVLO AC)</sub> switching level, arranging quick shut down when V<sub>CC SIM</sub> powers down
- · Integrated pull-up resistors; no external resistor required
- Integrated EMI Filters suppresses higher harmonics of digital I/O's
- A HIGH EN signal enables the translation of the signals
- Low current shutdown mode < 1 μA</li>
- Supports clock speed beyond 5 MHz clock
- Pb-free, Restriction of Hazardous Substances (RoHS) compliant and free of halogen and antimony (Dark Green compliant)
- ESD protection:
  - HBM: ANSI/ESDA/JEDEC JS-001 class 2 exceeds 2000 V
  - CDM: ANSI/ESDA/JEDEC JS-002 class C3 exceeds 1000 V
  - IEC61000-4-2 level 4, contact and air discharge on all SIM card-side pins are 8000 V and 15000 V
- Available in 10-pin XQFN package
- Specified from -40 °C to +85 °C

## 3. Applications

- NXT4557 can be used with a range of SIM card attached devices including:
  - · Mobile and personal phones
  - Wireless modems
  - SIM card terminals



### SIM card interface level translator with enable pin

# 4. Ordering information

#### **Table 1. Ordering information**

Туре	Package						
number	Temperature range	Name	Description	Version			
NXT4557GU	-40 °C to +85 °C	XQFN10	plastic, extremely thin quad flat package; no leads; 10 terminals; body 1.40 × 1.80 × 0.50 mm	SOT1160-1			

## 5. Marking

#### Table 2. Marking

Type number	Marking code[1]
NXT4557GU	z7

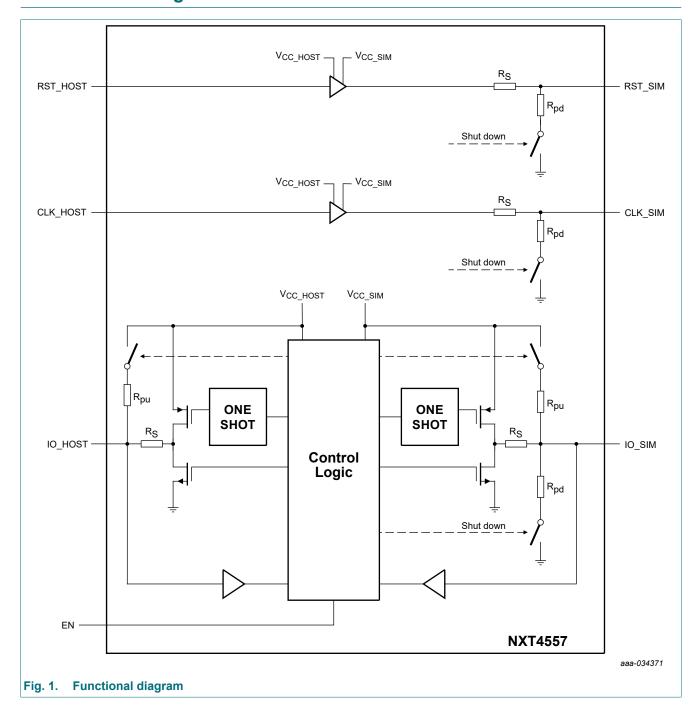
[1] The pin 1 indicator is located on the lower left corner of the device, below the marking code.

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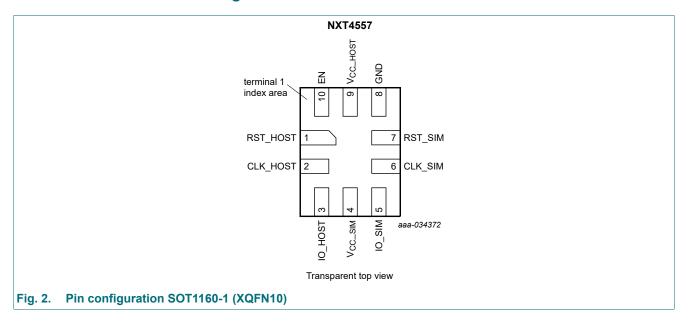
# 6. Functional diagram



SIM card interface level translator with enable pin

## 7. Pinning information

## 7.1. Pinning



## 7.2. Pin description

Table 3. Pin description

Symbol	Pin	Туре	Description
RST_HOST	1	I	Reset input from host controller.
CLK_HOST	2	I	Clock input from host controller.
IO_HOST	3	I/O	Host controller bidirectional data input/output. This pin can be driven from push pull as well as open drain drivers.
V <sub>CC_</sub> SIM	4	power	Supply voltage for the SIM CARD side input/output pins. This input voltage ranges from 1.62 V to 3.3 V. This pin should be bypassed with a 0.1 $\mu$ F ceramic capacitor close to the pin.
IO_SIM	5	I/O	SIM card bidirectional data input/output. The SIM card output must be on an open-drain driver.
CLK_SIM	6	0	Clock output pin for the SIM card.
RST_SIM	7	0	Reset output pin for the SIM card.
GND	8	ground	Ground for the SIM card and host controller. Proper grounding and bypassing are required to meet ESD specifications.
V <sub>CC_HOST</sub>	9	power	Supply voltage for the host controller side input/output pins (CLK_HOST, RST_HOST, IO_HOST). This pin should be bypassed with a 0.1 µF ceramic capacitor close to the pin.
EN	10	I	Enable input from host controller to enable or disable the translator. Also used to initiate shutdown sequence

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## 8. Functional description

#### 8.1. Functional behavior

The functional diagram of the NTX4557 is shown in Fig. 1.

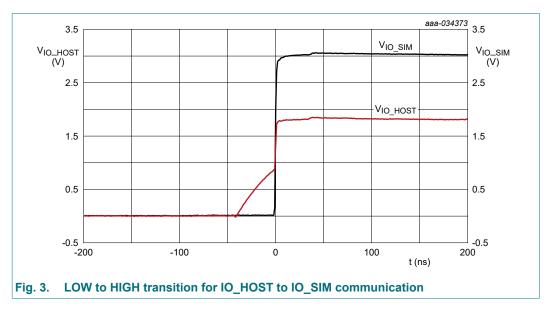
The upper part of Fig. 1 shows the RST and CLK channels which are uni-directional level shifters from the host to the SIM card side.

The bottom part shows the architecture of the bidirectional I/O channel. Both on IO\_HOST and IO\_SIM a resistor  $R_{pu}$  pulls up the I/O node. On both sides an output stage is present that consists of a PMOST and an NMOST device. Each output stage drives the output through a series resistor  $R_{S}$ . Input stages sense the I/O nodes and pass LOW/HIGH information to the control logic that controls the translator outputs and several pull-up and pull-down resistors.

The NXT4557 I/O channel does not require a dedicated input signal to control the direction of data flow from IO\_HOST to IO\_SIM or from IO\_SIM to IO\_HOST. Change in driving direction is possible when both sides are at HIGH state. The control logic recognizes the I/O node with the first falling edge and grants control over the opposite I/O node. When for example the IO\_HOST is turned LOW, the control circuit will turn on the NMOST on the IO\_SIM side, pulling LOW IO\_SIM. The IO\_SIM pin is then an output only, until IO\_HOST is turned HIGH and the translator has turned IO\_SIM HIGH again.

The PMOST devices are used to actively turn high the outputs. Each PMOST is driven by a one-shot circuit that generates a pulse. For example: Assuming HOST to SIM communication, when the IO\_HOST is turned HIGH, it will activate the one shot circuit on the IO\_SIM side. A pulse starts, arranging a fast LOW to HIGH transition on IO\_SIM. When the pulse has finished, the PMOST is released. At that stage, the system returns to a standard open drain state whereby the pull resistors keep the I/O nodes HIGH.

At the same time, at a LOW to HIGH transition, the one shot on the input side is activated as well. In an open drain application, this creates a typical input LOW to HIGH waveform. <u>Fig. 3</u> shows an example of a LOW to HIGH transition in an open drain application.



Looking at the input signal, the first part of the LOW to HIGH transition is an exponential curve caused by the I/O node capacitance being charged via the pull-up resistor. The second part starts when the input signal crosses the input switching level. The rising edge is accelerated dramatically by the PMOST that is turned on by the one shot on the input side.

In case of a communication error or some other unforeseen incident that may drive both connected sides of the drivers at the same time, the internal logic automatically prevents stuck-at situation. This ensures that both I/Os will return to HIGH level once released from being driven LOW.

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In shut down mode, the control circuit disables all output stages. Additionally, in shut down mode, the pull-up resistor on IO\_SIM side is disabled, and all pull-down resistors  $R_{pd}$  on SIM side are enabled, pulling LOW the pins on the SIM side. The shut down sequence is explained in more detail in Section 8.3.

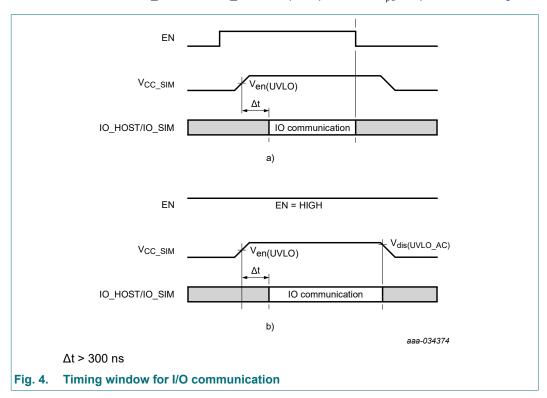
#### 8.2. Window of I/O communication

When the translator is in operating mode, I/O communication can take place through the I/O channel. Communication can take place in both directions IO\_HOST  $\leftrightarrow$  IO\_SIM. Additionally, during operating mode, the RST\_HOST and CLK\_HOST signals are passed to RST\_SIM and CLK\_SIM respectively.

The translator is active when EN is turned HIGH. Another condition for the operational mode is that  $V_{CC\_HOST}$  and  $V_{CC\_SIM}$  are at a proper level. Fig. 4 a)/b) shows two scenarios illustrating how EN and  $V_{CC\_SIM}$  control the translator mode.  $V_{CC\_HOST}$  is assumed to be default present and is not shown in the waveform.

When both EN and  $V_{CC\_SIM}$  have turned HIGH, I/O communication can commence after a certain amount of time:  $\Delta t > 300$  ns.

It is assumed that during the power up sequence, the nodes of IO\_HOST and and IO\_SIM are not pulled down by the host controller and the SIM card. The translator has integrated pull-up resistors and will turn HIGH both IO\_HOST and IO\_SIM. The pull-up resistors R<sub>pu</sub> are pointed out in <u>Fig. 1</u>.



When either EN turns low or  $V_{CC\_SIM}$  drops below  $V_{dis(UVLO)}$ , the translator turns to shutdown mode. Section 8.3 illustrates the shutdown sequence in more detail.

When EN turns low and during shutdown mode, the pull-down resistors are activated on all SIM card side pins (RST\_SIM, CLK\_SIM and IO\_SIM).

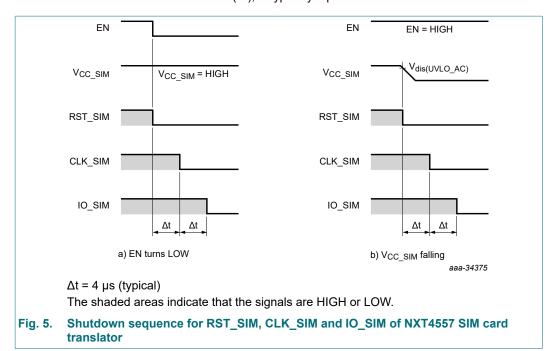
#### SIM card interface level translator with enable pin

#### 8.3. Shutdown sequence

The ISO 7816-3 specification specifies the shutdown sequence for the SIM card signals to ensure that the card is properly disabled for power savings. Also, during hot swap, the orderly shutdown of these signals helps to avoid any improper write and corruption of data.

When either the enable, EN, is asserted LOW or when  $V_{CC\_SIM}$  drops below  $V_{dis(UVLO\_AC)}$ , the shutdown sequence is initiated. Fig. 5 a) illustrates the shutdown sequence initiated by EN being asserted LOW. Fig. 5 b) illustrates the shutdown sequence initiated by  $V_{CC\_SIM}$  being powered down.

The shut down sequence starts by pulling down the RST\_SIM output. Once RST\_SIM is turned LOW, CLK\_SIM and IO\_SIM are pulled LOW sequentially, one-by-one. Internal pull-down resistors on the SIM pins are used to pull the SIM channels LOW. The internal pull-down resistors,  $R_{pd}$ , that pull down the three pins on the SIM side are shown in Fig. 1. The shutdown sequence is completed in a few microseconds. The interval time ( $\Delta t$ ), is typically 4  $\mu s$ .



#### 8.4. UVLO

When  $V_{CC\_SIM}$  drops below  $V_{dis(UVLO\_AC)}$ , the translator goes to shut down mode. This is illustrated in Fig. 4 b) and Fig. 5 b). The switching level  $V_{dis(UVLO\_AC)}$  has a high value of approximately 86 %x $V_{CC\_SIM}$ . The circuitry uses an AC detection mechanism that operates accurately with a falling slope that is typical in the SIM card application. Next to this AC detection, a standard UVLO detection is in place that has no condition with respect to the slope of the rising or falling  $V_{CC\_SIM}$ . For the standard UVLO, the parameters  $V_{en(UVLO)}$  and  $V_{dis(UVLO)}$  are involved which have lower values than  $V_{dis(UVLO\_AC)}$ . When  $V_{CC\_SIM}$  is powered up, the translator is enabled when  $V_{CC\_SIM}$  crosses  $V_{en(UVLO)}$ . This is illustrated in Fig. 4 a)/b).

#### 8.5. EMI filter

All output driver stages of I/O, RST and CLK channels are equipped with EMI filters to reduce interference towards sensitive mobile communication.

#### 8.6. ESD protection

The device has robust ESD protections on all SIM card pins. The architecture prevents any stress for the host: the voltage translator discharges any stress to supply ground.

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#### SIM card interface level translator with enable pin

## 9. Limiting values

#### **Table 4. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>ESD</sub>	electrostatic discharge voltage	SIM card side; IEC 61000-4-2, level 4; contact discharge	-	±8	kV
		SIM card side; IEC 61000-4-2, level 4; air discharge	-	±15	kV
		all other pins; IEC 61000-4-2, level 4; contact discharge	-	±2	kV
		all other pins; HBM [1]	-	±2	kV
		all other pins; CDM [2]	-	±1	kV
V <sub>CC_HOST</sub>	supply voltage		GND - 0.5	4.6	V
V <sub>CC_SIM</sub>	SIM card supply voltage		GND - 0.5	4.6	V
VI	input voltage	CLK_HOST; input signal voltage, HOST side	GND - 0.5	4.6	V
		RST_HOST; input signal voltage, HOST side	GND - 0.5	4.6	V
		IO_HOST; input signal voltage, HOST side	GND - 0.5	4.6	V
		EN; enable input voltage, HOST side	GND - 0.5	4.6	V
		CLK_SIM; input signal voltage, SIM side	GND - 0.5	4.6	V
		RST_SIM; input signal voltage, SIM side	GND - 0.5	4.6	V
		IO_SIM; input signal voltage, SIM side	GND - 0.5	4.6	V
T <sub>stg</sub>	storage temperature		-55	+125	°C

<sup>[1]</sup> Human Body Model (HBM) according to JESD22-A-A114.

# 10. Recommended operating conditions

**Table 5. Operating conditions** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>CC_HOST</sub>	supply voltage	[1]	1.08	-	1.98 V	V
V <sub>CC_SIM</sub>	card side supply voltage	[1]	1.62	-	3.3	V
VI	input voltage	HOST side	-0.3	-	V <sub>CC_HOST</sub> + 0.3	V
		SIM side	-0.3	-	V <sub>CC_SIM</sub> + 0.3	V
T <sub>amb</sub>	ambient temperature		-40	+25	+85	°C

[1]  $V_{CC\_SIM} \ge V_{CC\_HOST}$ 

<sup>[2]</sup> Charged-Device Model (CDM) according to JESD22-C101.

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## 11. Electrical characteristics

#### **Table 6. Electrical characteristics**

 $1.08~V \le V_{CC~HOST} \le 1.98~V;~1.62~V \le V_{CC~SIM} \le 3.3~V;~GND = 0~V;~unless~otherwise~specified.$ 

Symbol	Parameter	Conditions		Tan	<sub>nb</sub> = -40 °C to +85	5 °C	Unit
				Min	Typ[1]	Max	
I <sub>CC_HOST</sub>	supply current	operating mode; f <sub>clk</sub> = 1 MHz; IO_HOST = IO_SIM = HIGH	[2]	-	5	10	μΑ
		shutdown mode; IO_HOST = HIGH	[3]	-	-	1	μΑ
I <sub>CC_SIM</sub>	card side supply current	operating mode; IO_HOST = IO_SIM = HIGH; CLK_HOST = RST_HOST = LOW	perating mode; [2] D_HOST = IO_SIM = HIGH;		2	8	μΑ
V <sub>en(UVLO)</sub>	undervoltage lockout enable voltage	V <sub>CC_SIM</sub> rising; V <sub>CC_HOST</sub> = 1.8 V	V <sub>CC_SIM</sub> rising; V <sub>CC_HOST</sub> = 1.8 V		1.2	1.6	V
V <sub>dis(UVLO)</sub>	undervoltage lockout disable voltage	V <sub>CC_SIM</sub> falling; V <sub>CC_HOST</sub> = 1.8 V		0.65	1.0	1.3	V
V <sub>dis(UVLO_AC)</sub>		V <sub>CC_SIM</sub> falling;					
	lockout disable voltage	-dV/dt = 0.9 V/ms to 9 V/ms; V <sub>CC_SIM</sub> = 1.8 V		-	1.55	-	V
		-dV/dt = 1.5 V/ms to 15 V/ms; V <sub>CC_SIM</sub> = 3.0 V		-	2.58	-	V
		-dV/dt = 0.9 V/ms to 9 V/ms; V <sub>CC_SIM</sub> = 1.71 V to 1.89 V		-	0.86V <sub>CC_SIM</sub>	-	V
		-dV/dt = 1.5 V/ms to 15 V/ms; V <sub>CC_SIM</sub> = 2.85 V to 3.15 V		-	0.86V <sub>CC_SIM</sub>	-	V

<sup>[1]</sup> Typical values measured at 25 °C.

<sup>[2]</sup> Internal pull-up resistance active on IO\_HOST and IO\_SIM

<sup>[3]</sup> Internal pull-up resistance active on IO\_HOST

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**Table 7. Static characteristics** 

 $1.08 \ V \leq V_{CC\_HOST} \leq 1.98 \ V; \ 1.62 \ V \leq V_{CC\_SIM} \leq 3.3 \ V; \ GND = 0 \ V; \ unless \ otherwise \ specified.$ 

Parameter	Conditions	T <sub>amt</sub>	$T_{amb}$ = -40 °C to +85 °C				
		Min	Typ[1]	Max			
ifter						•	
HIGH-level	RST_HOST, CLK_HOST, EN [2] 0		0.65V <sub>CC_HOST</sub>	-	V <sub>CC_HOST</sub> + 0.3	V	
input voltage	IO_HOST	[2]	0.5V <sub>CC_HOST</sub>	-	V <sub>CC_HOST</sub> + 0.3	V	
	IO_SIM	[2]	0.5V <sub>CC_SIM</sub>	-	V <sub>CC_SIM</sub> + 0.3	V	
LOW-level	RST_HOST, CLK_HOST, EN	[2]	-0.3	-	0.35V <sub>CC_HOST</sub>	V	
input voltage	IO_HOST	[2]	-0.3	-	0.3V <sub>CC_HOST</sub>	V	
	IO_SIM	[2]	-0.3	-	0.25V <sub>CC_SIM</sub>	V	
pull-up	IO_SIM connected to V <sub>CC_SIM</sub>		3.3	5.3	7.3	kΩ	
resistance	IO_HOST connected to V <sub>CC_HOST</sub>		2.8	4.3	6	kΩ	
HIGH-level	RST_SIM, CLK_SIM; I <sub>OH</sub> = -1 mA		0.85V <sub>CC_SIM</sub>	-	V <sub>CC_SIM</sub> +0.3	V	
output voltage	IO_SIM; I <sub>OH</sub> = -10 μA		0.85V <sub>CC_SIM</sub>	-	V <sub>CC_SIM</sub> +0.3	V	
	IO_HOST; I <sub>OH</sub> = -10 μA		0.85V <sub>CC_HOST</sub>	-	V <sub>CC_SIM</sub> +0.3	V	
LOW-level	RST_SIM, CLK_SIM; I <sub>OL</sub> = 1 mA		-	50	200	mV	
output voltage	IO_SIM; I <sub>OL</sub> = 1 mA		-	50	300	mV	
	IO_HOST; I <sub>OL</sub> = 1 mA		-	50	300	mV	
pull-down resistance	CLK_SIM, RST_SIM, IO_SIM		-	400	-	Ω	
r							
series	IO_SIM		-	44	-	Ω	
resistance	RST_SIM		-	44	-	Ω	
	CLK_SIM		-	44	-	Ω	
input/output	IO_SIM		-	10	-	pF	
capacitance	RST_SIM		-	10	-	pF	
	CLK_SIM		-	10	-	pF	
	Ifter  HIGH-level input voltage  LOW-level input voltage  pull-up resistance  HIGH-level output voltage  LOW-level output voltage  pull-down resistance  r  series resistance	HIGH-level input voltage    RST_HOST, CLK_HOST, EN     IO_HOST     IO_SIM     RST_HOST, CLK_HOST, EN     IO_HOST     IO_SIM     Pull-up resistance     IO_HOST     IO_SIM     IO_HOST     IO_SIM     IO_HOST     IO_HOST     IO_SIM     IO_HOST     IO_SIM     IO_HOST     IO_SIM     IO_SI	HIGH-level   Input voltage   RST_HOST, CLK_HOST, EN   [2]   IO_HOST   IO_SIM   [2]   IO_HOST   IO_SIM   [2]   IO_HOST   IO_SIM   IO_HOST   IO_SIM   IO_SIM   IO_SIM   IO_HOST   IO_SIM   IO_HOST   IO_HOST	HIGH-level input voltage   RST_HOST, CLK_HOST, EN   [2]   0.65V <sub>CC_HOST</sub>   IO_HOST   IO_SIM   [2]   0.5V <sub>CC_SIM</sub>   IO_HOST   IO_SIM   [2]   0.5V <sub>CC_SIM</sub>   IO_HOST   IO_SIM   IO_HOST   IO_SIM   IO_HOST   IO_SIM   IO_HOST   IO_SIM   IO_HOST   IO_SIM   IO_HOST   IO_	Min   Typ[1]	Min   Typ[1]   Max	

<sup>[1]</sup> Typical values measured at 25 °C.

<sup>[2]</sup>  $V_{\text{IL}}$ ,  $V_{\text{IH}}$  depend on the individual supply voltage per interface.

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#### **Table 8. Dynamic characteristics**

push-pull: test circuit see Fig. 7;  $C_L = 50 pF$ ;

open-drain: test circuit see Fig. 8;  $C_{IO\_HOST}$  = 10 pF;  $C_{IO\_SIM}$  = 30 pF

For waveform see Fig. 6

Symbol Parameter		Conditions		T <sub>amb</sub> = -40 °C to +85 °C						
				V <sub>CC_SIM</sub> = 1.8 V ± 0.18 V			V <sub>CC_SI</sub>	<sub>M</sub> = 3.0 V	± 0.3 V	
				Min	Typ[1]	Max	Min	Typ[1]	Max	
V <sub>CC_HOS</sub>	<sub>ST</sub> = 1.2 V ± 0.12	V								
t <sub>pd</sub>	propagation	I/O channel; push-pull	[2]	-	12	20	-	12	20	ns
	delay	I/O channel; open-drain		-	15	25	-	15	25	ns
		CLK and RST channels; push-pull		-	12	20	-	12	20	ns
t <sub>t</sub>	transition time	IO_HOST; push-pull	[3]	-	-	10	-	-	10	ns
		IO_SIM; RST_SIM; CLK_SIM; push-pull		-	-	10	-	-	10	ns
t <sub>sk</sub>	skew time	between channels IO_SIM and CLK_SIM; push-pull		-	2	-	-	2	-	ns
f <sub>clock</sub>	clock frequency	CLK channel; push-pull	[4]	-	-	25	-	-	25	MHz
f <sub>data</sub>	data rate	I/O channel; push-pull	[4]	-	-	5	-	-	5	Mbps
		I/O channel; open-drain; see Fig. 8	[4]	-	-	800	-	-	800	kbps
V <sub>CC_HOS</sub>	<sub>ST</sub> = 1.8 V ± 0.18	V								
t <sub>pd</sub>	propagation	I/O channel; push-pull	[2]	-	7	12	-	7	12	ns
	delay	I/O channel; open-drain		-	8	15	-	8	15	ns
		CLK and RST channels; push-pull		-	7	12	-	7	12	ns
t <sub>t</sub>	transition time	IO_HOST; push-pull	[3]	-	-	10	-	-	10	ns
		IO_SIM; RST_SIM; CLK_SIM; push-pull		-	-	10	-	-	10	ns
t <sub>sk</sub>	skew time	between channels IO_SIM and CLK_SIM; push-pull		-	2	-	-	2	-	ns
f <sub>clock</sub>	clock frequency	CLK channel; push-pull	[4]	-	-	25	-	-	25	MHz
f <sub>data</sub>	data rate	I/O channel; push-pull	[4]	-	-	5	-	-	5	Mbps
		I/O channel; open-drain; see Fig. 8	[4]	-	-	800	-	-	800	kbps

Typical values measured at 25 °C.

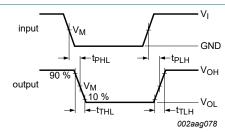
<sup>[2]</sup>  $t_{\text{pd}}$  is the same as  $t_{\text{PHL}}$  and  $t_{\text{PLH}}.$ 

<sup>[3]</sup> 

 $t_t$  is the same as  $t_{THL}$  and  $t_{TLH}$ . Criteria: duty cycle between 40% and 60%; Voltage swing between 10%  $V_{CCI}$  and 90%  $V_{CCI}$ .

#### SIM card interface level translator with enable pin

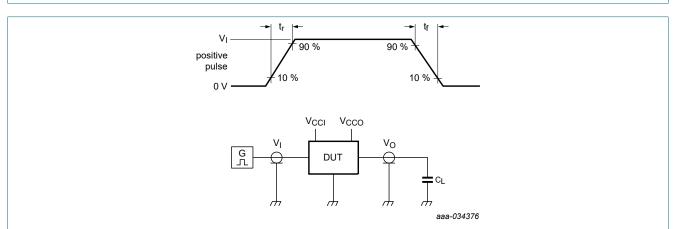
### 11.1. Waveforms and test circuits



Measurement points are given in Table 8.

V<sub>OL</sub> and V<sub>OH</sub> are typical output voltage levels that occur with the output load.

Fig. 6. Data input to data output propagation delay times



Test data is given in Table 9.

All input pulses are supplied by generators having the following characteristics:

PRR  $\leq$  10 MHz;  $Z_O = 50 \Omega$ ;  $t_r$ ,  $t_f \leq$  2.5 ns.

Definitions test circuit:

C<sub>L</sub> = Load capacitance including jig and probe capacitance;

 $\ensuremath{V_{\text{CCI}}}$  is the supply voltage associated with the input;

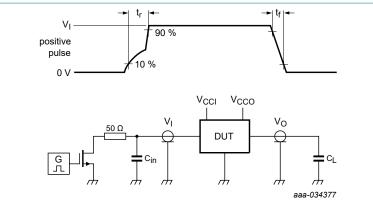
 $\ensuremath{V_{\text{CCO}}}$  is the supply voltage associated with the output.

Fig. 7. Test circuit for measuring switching times for push-pull drive

Table 9. Test data for push-pull drive

Supply voltage		Direction	Input		Output	Load
V <sub>CC_HOST</sub>	V <sub>CC_SIM</sub>		V <sub>I</sub>	V <sub>M</sub>	V <sub>M</sub>	CL
1.08 V to 1.98 V	1.62 V to 3.3 V	host side to SIM card side	V <sub>CC_HOST</sub>	0.5V <sub>CC_HOST</sub>	0.5V <sub>CC_SIM</sub>	50 pF
1.08 V to 1.98 V	1.62 V to 3.3 V	SIM card side to host side	V <sub>CC_SIM</sub>	0.5V <sub>CC_SIM</sub>	0.5V <sub>CC_HOST</sub>	50 pF

#### SIM card interface level translator with enable pin



Test data is given in Table 10.

Pulse generator (G) has the following characteristics:

PRR ≤ 10 MHz;  $Z_0$  = 50  $\Omega$ ;  $t_r$ ,  $t_f$  ≤ 2.5 ns.

Definitions test circuit:

C<sub>L</sub> = Load capacitance including jig and probe capacitance;

V<sub>CCI</sub> is the supply voltage associated with the input;

V<sub>CCO</sub> is the supply voltage associated with the output;

Rise time on input pin strongly depends on source impedance, internal pull-up resistor and load capacitance (Cin).

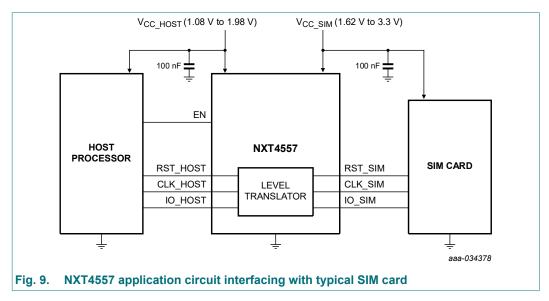
#### Fig. 8. Test circuit for measuring switching times for open drain drive

Table 10. Test data for open drain drive

Supply voltage		Direction	Input		Input		Input		Input		Input		Input		Input		Output	Load	
V <sub>CC_HOST</sub>	V <sub>CC_SIM</sub>		V <sub>I</sub>	V <sub>M</sub>	V <sub>M</sub>	C <sub>in</sub>	CL												
1.08 V to 1.98 V	1.62 V to 3.3 V	host side to SIM card side	V <sub>CC_HOST</sub>	0.6V <sub>CC_HOST</sub>	0.6V <sub>CC_SIM</sub>	10 pF	30 pF												
1.08 V to 1.98 V	1.62 V to 3.3 V	SIM card side to host side	V <sub>CC_SIM</sub>	0.5V <sub>CC_SIM</sub>	0.5V <sub>CC_HOST</sub>	30 pF	10 pF												

## 12. Application information

The application circuit for the NXT4557, which shows the typical interface with a SIM card, is shown in <u>Fig. 9</u>. Supply decoupling capacitors (100 nF) are recommended and should be placed close to the translator product.



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#### SIM card interface level translator with enable pin

## 13. Package outline

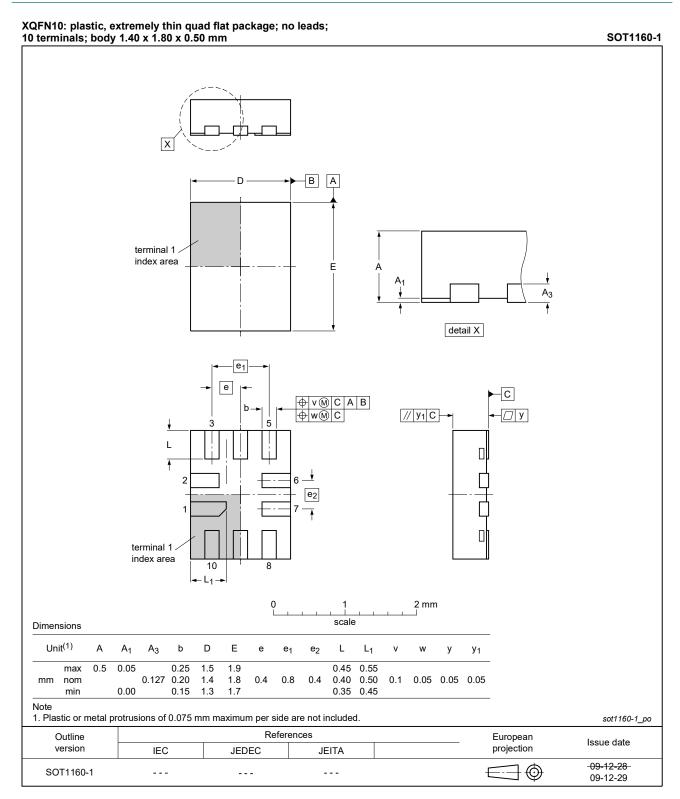


Fig. 10. Package outline SOT1160-1 (XQFN10)

### SIM card interface level translator with enable pin

## 14. Abbreviations

#### **Table 11. Abbreviations**

Acronym	Description		
ANSI	American National Standards Institute		
CDM	Charged-Device Model		
ESD	ElectroStatic Discharge		
ESDA	ElectroStatic Discharge Association		
НВМ	Human Body Model		
JEDEC	Joint Electron Device Engineering Council		
MSL	Moisture Sensitivity Level		
PCB	Printed-Circuit Board		
SIM	ubscriber Identification Module		

# 15. Revision history

#### **Table 12. Revision history**

Document ID	Release date	Data sheet status	Change notice	Supersedes				
NXT4557 v.2.2	20240731	Product data sheet	-	NXT4557 v.2.1				
NXT4557 v.2.1	20230522	Product data sheet	-	NXT4557 v.1				
Modifications:	_	corrected (errata). cted (errata).						
NXT4557 v.1	20220203	Product data sheet	-	-				

### 16. Legal information

#### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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